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<b>Substitute for form 1449A/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>Application Number</b>	10/061,945
				<b>Filing Date</b>	1/31/2002
				<b>First Named Inventor</b>	Steven Teig, et al.
				<b>Group Art Unit</b>	<del>2000</del> 2825
				<b>Examiner Name</b>	J. WHITMORE
<b>Sheet</b>	1	of	3	<b>Attorney Docket Number</b>	SPLX.P0063 (2002-097)

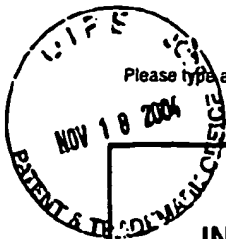
U.S. PATENT APPLICATIONS						
Examiner Initials	Cite No. <sup>1</sup>	U.S. Patent Application		Name of Patentee or Applicant of Cited Document	Date of Filing MM-DD-YYYY	Related Application Data (if any)
		Serial Number	Attorney Docket No.			
JW	1.	10/335,247	CDN.P0053	Steven Teig et al.	12-31-2002	
	2.	10/335,097	CDN.P0054	Steven Teig et al.	12-31-2002	
	3.	10/335,248	CDN.P0055	Steven Teig et al.	12-31-2002	
	4.	10/335,095	CDN.P0056	Steven Teig et al.	12-31-2002	
	5.	10/334,664	CDN.P0057	Steven Teig et al.	12-31-2002	
	6.	10/062,264	SPLX.P0062	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	7.	10/062,184	SPLX.P0064	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	8.	10/066,326	SPLX.P0110	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	9.	10/062,193	SPLX.P0112	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.
	10.	10/062,196	SPLX.P0113	Steven Teig et al.	01-31-2002	Application filed on the same day as the present application with the same specification and drawings.

<b>Examiner Signature</b>		<b>Date Considered</b>	8/16/05
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				<b>Group Art Unit</b>	<del>2025</del>
				<b>Examiner Name</b>	S. WHITMORE
<b>Sheet</b>	2	of	3	<b>Attorney Docket Number</b>	SPLX.P0063 (2002-097)

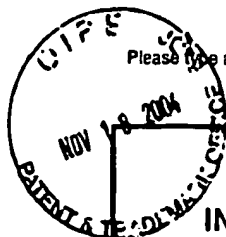
NON PATENT LITERATURE DOCUMENTS				
Examiner's Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>	
AW	11.	BRAMBILLA, A. et al., Statistical Method for the Analysis of Interconnects Delay in Submicrometer Layouts, IEEE, 8/2001, pp. 957-966.		
	12.	BRANDT et al., Circuit Multi-fault Diagnosis and Prediction Error Estimation Using a Committee of Bayesian Neural Networks, IEEE, Colloquium on Testing Mixed Signal Circuits and Systems, 23 October, 1997, pp. 7/1-7/7.		
	13.	FERTIG, "Extracting Knowledge from Case Databases", Apr. 1991, IEEE Proceedings on Seventeenth Annual Northeast Bioengineering Conference, pp. 267-268.		
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	16.	IDA et al., Bayesian Analysis in Manufacturing Instrumentation for Test and Evaluation, IEEE, Conference record of 1993 Fourth Fifth Annual Conference of Electrical Engineering Problems and Plastics Industries, 27 April 1993, pp.4-13.		
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	18.	LI et al., Monte Carlo Simulation Techniques for Probabilistic Tracking, IEEE, 2001, pp.75-82.		
	19.	LI et al., Pre-extracting Support Vectors for Support Vector Machine", Aug. 2000, IEEE Proceedings of 5th International Conference on Signal Processing, vol. 3, pp. 1432-1435.		
	20.	MANI, N., A Neural Network Model for Partitioning in Floorplan Design, IEEE, pp.1676-1680.		
	21.	NIU et al., A Bayesian Approach to Variable screening for Modeling the IC Fabrication Process, 1995, IEEE International Symposium on Circuits and Systems, Vol. 2, 30 April 1995, pp. 1227-1230.		
	22.	NN9107436, Maximum Likelihood Training of Probabilistic Linear Functions (Probabilistic Perceptrons), IBM Technical Disclosure Bulletin, vol. 34, No. 2, July 1991. pp.436-442.		
	23.	RUPING, S., Incremental Learning with Support Vector Machines, Dec. 2001, IEEE Proceedings of Internal Conference on Data Mining, pp. 641-642.		

<b>Examiner Signature</b>	AW	<b>Date Considered</b>	8/16/05
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<b>Sheet</b>	3	of	3	<b>Attorney Docket Number</b>	SPLX.P0063 (2002-097)

NON PATENT LITERATURE DOCUMENTS		
<input checked="" type="checkbox"/>	24.	SUYKENS, Nonlinear Modelling and Support Vector Machines, May 2001, IEEE Proceedings of the 18 <sup>th</sup> Instrumentation and Measurement Technology Conference, vol 1, pp. 287-294.
<input checked="" type="checkbox"/>	25.	VEHTARI et al., Bayesian Neural networks for Industrial Applications, Proceedings of the 1999 IEEE Midnight-Sun Workshop on Soft Computing Methods in Industrial Applications, 16 June 1999, pp.63-68.
<input checked="" type="checkbox"/>	26.	WANG et al., Accurate Parasitic Resistance Extraction for Interconnection Analysis, 1995, IEEE, Custom integrated circuits conference, 255-258.
<input checked="" type="checkbox"/>	27.	WRIGHT, W.A., Bayesian Approach to Neutral Network Modeling with Input Uncertainty, IEEE, Nov. 1999, pp. 1261-1270.
<input checked="" type="checkbox"/>	28.	YERRAMAREDDY et al., Creating and Using Models for Engineering Design A Machine-Learning Approach, Jun. 1992, IEEE Intelligent Systems, vol. 7, iss. 3, pp.52-59.
<input checked="" type="checkbox"/>	29.	ZHANG et al., Confidence Regions for Cascaded Neural Network Prediction in Power Markets, 2001 Power Engineering Society Winter Meeting, vol. 2, 28 January 2001, pp.533-538.
<input checked="" type="checkbox"/>	30.	ZHANG, C.X. et al., Floorplan Design Using a Hierarchical Neural Learning Algorithm, IEEE, 6/1991, pp. 2060-2063.

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11/16/04

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

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Title of Invention	Method and apparatus for creating an extraction model
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Application Number : 10/061945  
 Confirmation Number: 8774  
 First Named Applicant: Steven Teig  
 Attorney Docket Number: SPLX.P0063  
 Art Unit: 2123  
 Examiner:



Search string: ( 4300196 or 4839823 or 5276632 or 5452224 or 5642296 or 5689621 or 5808919 or 5822218 or 5901063 or 5903469 or 6018623 or 6038338 or 6038383 or 6061508 or 6128768 or 6182269 or 6189131 or 6209123 or 6212492 or 6243653 or 6304836 or 6304837 or 6327556 or 6381555 or 6414498 or 6430729 or 6446027 or 6526549 or 6543035 or 6549854 or 6581195 or 6581198 or 6584456 or 6587997 or 6687887 or 6735748 or 20020010691 or 20020056070 or 20020075383 or 20030065535 or 20030236760 or 20040049751 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
AW	1	4300196	1981-11-30	Lopresti			
	2	4839823	1986-06-13	Matsumoto			
	3	5276632	1994-01-04	Corwin et al.			
	4	5452224	1995-09-19	Smith et al.			
	5	5642296	1997-06-24	Saxena			
	6	5689621	1997-11-18	Salam et al.			
	7	5808919	1998-09-15	Preist et al.			
	8	5822218	1998-10-13	Moosa et al.			
	9	5901063	1999-05-04	Chang et al.			
	10	5903469	1999-05-11	Ho			
	11	6018623	2000-01-25	Chang et al.			
	12	6038338	2000-03-14	Nguyen			
	13	6038383	2000-03-14	Young et al.			
	14	6061508	2000-05-09	Mehrotra et al.			
	15	6128768	2000-10-03	Ho			
	16	6182269	2001-01-30	Laubhan	B1		
	17	6189131	2001-02-13	Graef et al.	B1		
	18	6209123	2001-03-27	Maziasz et al.	B1		
AW	19	6212492	2001-04-03	Kuge	B1		

AW

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W	20	6243653	2001-06-05	Findley	B1		
	21	6304836	2001-10-16	Krivokapic et al.	B1		
	22	6304837	2001-10-16	Geiger et al.	B1		
	23	6327556	2001-12-04	Geiger et al.	B1		
	24	6381555	2002-04-30	Sewell	B1		
	25	6414498	2002-07-02	Chen	B2		
	26	6430729	2002-08-06	Dewey et al.	B1		
	27	6446027	2002-09-03	O Keefe et al.	B1		
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	32	6581198	2003-06-17	Teig et al.	B1		
	33	6584456	2003-06-24	Dom et al.	B1		
	34	6587997	2003-07-01	Chen et al.	B1		
	35	6687887	2004-02-03	Teig et al.	B1		
▼	36	6735748	2004-05-11	Teig et al.	B1		

### US Published Applications

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init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
W	1	20020010691	2002-01-24	Chen	A1		
	2	20020056070	2002-05-09	Tanaka	A1		
	3	20020075383	2002-06-20	Trobaugh et al.	A1		
	4	20030065535	2003-04-03	Karlov et al.	A1		
	5	20030236760	2003-12-25	Nugent	A1		
▼	6	20040049751	2004-03-11	Teig et al.	A1		

### Signature

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AW	8/16/05